REPORT



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FINAL REPORT

COMMAND AND COMMUNICATION SYSTEM TEST SET

GROUND SUPPORT EQUIPMENT (
CONTRACT NO. NAS 8-20546

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1.0 INTRODUCTION AND SUMMARY

Motorola is submitting this final report to complete the final requirements of Contract NAS 8-20546. It covers the period from June 1, 1966 to September 1, 1966. In addition, it summarizes some of the significant events of the CCS Test Set program since the beginning. Included are technical achievements, schedules, additional test data, and recommendations.

SECTION II

2.0 REVIEW AND ACCOMPLISHMENTS

2.1 SUMMARY OF SCOPE AND CHANGES

The contract was signed on 3 December 1965. It provided for the delivery of five (5) Command & Communications System (CCS) Transponder Test Sets with suitable documentation, and limited personnel training at both Kennedy Space Center (KSC) and Marshall Space Flight Center (MSFC). Delivery of the first unit was initially scheduled to be 17 weeks after contract award. Subsequent units were scheduled to be delivered in 3-week intervals, except that the last 2 were to be delivered concurrently. The actual shipping dates agreed upon, test set configuration, and destination are summarized as follows:

Date	Serial No.	To	Type of Racks	Inter-rack Cabling
4 April	l	"MSFC (for IBM)	Motorola	Top
25 April	2	KSC	CFE	Top
16 May	3	MSFC (for IBM)	Motorola	Top
6 June	14	KSC	GFE	Тор
6 June	5	MSFC	Motorola	Lower-Rear

On 3 January 1966, Motorola was verbally redirected to provide an automatic precision ranging system in place of the one specified in the original work statement. Significant features of this system were ago of the clock, automatic code acquisition, and a 1 nanosecond resolution Range Delay Counter. It was agreed that Test Set S/N's 1, 2, and 3 would be delivered without any ranging system. Serial No.'s 4 and 5 would have the ranging capability included at delivery. Then S/N's 1, 2, and 3 would be retrofitted in the field at 3-week intervals following the delivery of the last test set.

During a subsequent meeting in January, other changes were discussed in addition to the ranging and were later incorporated into the system by a contract Modification Number 2. These items were:

- 1. The addition of an automatic sweep decay circuit for use in carrier acquisition tests.
- 2. The addition of a 600 kHz VCO in each of the 5 systems.
- 3. Addition of the capability to adjust the output of the TWT Power Amplifier continuously.
- 4. The addition of an audio monitor for the receiver and 2 head sets in each of the 5 systems.
- 5. Provisions for a 100K output impedance on the transponder telemetry functions. These were originally specified to be 10K.
- 6. Change the input to the PCM Telemetry 1.024 MHz Bi-Phase Modulator from single-ended to double-ended balanced to ground at the front panel of the modulation control.
- 7. Provide 5-20 MHz crystal filters with 2 kHz bandpass, for installation on the Hewlett-Packard RF Spectrum Analyzer.
- 8. Make provisions for monitoring the external telemetry function of the transponder when the Test Set is in the VAB or PAD modes.
- 9. Add a drawer (Antenna Status drawer) with lights, amplifiers, and power supply for the purpose of monitoring the condition of r-f switches external to the Test Set.

Due to above changes, a revised delivery schedule was agreed upon which is summarized as follows:

Test Sets	Shipping Date	Destination
S/N 1	4-13-66	MSFC
S/N 2	4-28-66	KSC
s/n 3	5-14-66	MSFC
s/n 4	6-23-66	MS FC
S/N 5	6-8-66	KSC
	2 ~2	

Ranging Retrofit to be included in S/N 4 and S/N 5.

Retrofit for	Shipping Date
S/N l	6-23-66
S/N 2	6-8-66
s/N 3	6-23-66

During February and March, the program slipped behind schedule due to a variety of problems, such as parts shortages, the impact of the changes, and technical problems associated with the first unit. During April a meeting was held with key personnel from both MSFC and Motorola. Technical and schedule problems were discussed in detail. MSFC requested a firm schedule commitment from Motorola for all deliverable items. Motorola assured MSFC that major emphasis was being placed on the program. The revised schedule was presented to MSFC and is summarized.

DELIVERABLE ITEMS	DELIVERY SCHEDULE AT DESTINATION (Assuming Shipment in an Electronic Van)
Test Set	,
S/N 1, less Ranging	5-14-66
S/N 2, less Ranging	6-20-66
S/N 3, less Ranging	7-10-66
S/N 5, complete	8-10-66
S/N 4, complete	8-28-66
Ranging Retrofit	
S/N 1 and S/N 3	8-28-66
3/N 2	8-10-66
Antenna Status Panel	
S/N 1	6-15-66
S/N 2	6-30-66
S/N 3, 4, 5	Concurrent with Test Set S/N 3, 4, 5

DELIVERY SCHEDULE AT DESTINATION (Assuming Shipment in an Electronic Van)

Set

DELIVERABLE ITEMS

Documentation				
Preliminary Draft Documentation	Concurrent with Test S/N 1, 2, 3			
Final Documentation with copies concurrent with -				
2 ea Test Set S/N 5	8-10-66			
2 ea Test Set S/N 2, Retrofit	8-10-66			
2 ea Test Set S/N 1, 3, Retrofit	8-28-66			
2 ea Test Set S/N 4	8-28-66			
Documentation Reproducibles, 2 ea	9-1-66			
Final Report	9 - 8-66			
Full Size Documentation Reproducibl	.es 9-8-66			

After the checkout and test of System No. 1, technical problems were uncovered which Motorola investigated on subsequent units. Numerous meetings were held to determine how important the problems were and the extent of the fixes. These problems were:

- 1. VCO phase jitter was within spec, but it was felt that it could be improved.
- 2. The r-f leakage was not completely covered by the specification and some deficiencies were found.
- 3. PCM driver did not meet all of the desired requirements, although it did meet the procurement specification.
- The Hughes TWT Amplifier did not meet the RFI specification.
- 5. A transient was observed when switching between MCC and ACC which was out of spec.
- Sporadic oscillation in the receiver AGC loop.

It was agreed that all but the MGC/AGC transient would be fixed either prior to delivery or in the field as a retrofit. A more detailed discussion of the problems and solutions follow.

The r-f leakage problem included: (1) The Test Transmitter leaking into the Transponder Receiver during the Self Test mode; (2) the Transponder Transmitter output leaking into the Test Receiver during the Self Test and VAB modes; and (3) the Test Transmitter output leaking into the Transponder Receiver, around the uplink attenuator, in VAB and PAD modes. The first two problems were resolved by relocating some of the coaxial relays and installing rigid coaxial cables in appropriate places. The third problem was corrected by relocation and shielding of a coaxial relay; shielding an isolator; and soldering rigid coaxial cable to connectors.

The VCO phase jitter problem was evaluated during checkout of S/N 1. A new ruggedized crystal mount was incorporated and a new circuit layout was implemented on later units. As a result of the design improvement, the performance of the later VCO's was found to be reliable and repeatable. The combined transmitter/receiver phase jitter over the total tuning range averaged between 4° to 4.5° rms in the 40 Hz loop. The specification required a maximum of 7°.

It was agreed that the PCM driver module would be redesigned. This was accomplished and the new module was found to meet all of the requirements necessary
to interface with the transponder.

The first delivered Hughes TWT Amplifier failed to meet the radiated interference limits of MIL-I-6181 and was returned to the vendor for repair. It was repaired and retested at Motorola. The tests proved successful and the unit was shipped to KSC for installation in S/N 2 Test Set. The improvements made in the first TWT were incorporated in the second unit prior to shipment from Hughes.

The receiver AGC amplifier oscillation was evaluated and fixed with the addition of a capacitor.

The various problems and associated solutions were implemented prior to delivery or as part of a field retrofit program.

Table II-1 summarized the status of the Test Sets as they were delivered and the retrofits performed.

2.2 REVIEW OF SCHEDULED AND ACTUAL DELIVERY DATES

The following summary indicates schedule performance with respect to delivery of completed hardware.

	ITEM DESCRIPTION	ORIG SCHED DEL DATE	REVISED DEL DATE	ACTUAL SHIPPING DATE
1.	Test Set S/N l (less Ranging and Antenna Status Panel)	4-13-66	5 - 11 ₁ -66	5-7-66
2.	Test Set S/N 2 (less Hanging and Antenna Status Panel)	4-28-66	6-20-66	6-6-66 Note 1.
3.	Test Set S/N 3 (less Ranging)	5-4-66	7-10-66	6-24-66 Note 2.
4.	Test Set S/N 4	6-23-66	9 - 1-66	8-1-66
5.	Test Set S/N 5	6-8-66	8-14-66	7-20-66
6.	Ranging Equipment (Retrofit for S/N 1)	6-23-66	9-1-66	7 - 29-66
7.	Antenna Status Panel & 600 kHz Osc. for S/N 2	Not Applicable	6-30-66	6-11-66
8.	Antenna Status Panel & (30) Mtg. Osc. for S/N l	Not Applienble	6-15-66	6-30-66

- Note 1. Test Set S/N 2 was originally scheduled to be delivered tess Ranging Equipment; however, it was possible to incorporate the Ranging Equipment in this set and avoid the retrofit effort. This was done at some delay in shipment of the Test Set.
- Note 2. Test Set S/N 3 was originally scheduled to be delivered without Ranging Equipment and retrofitted. This was not necessary as Ranging Equipment was available in time to be incorporated in S/M 3.

	VOO Ø Jitter	New PCM Driver	Install & Update Ranging	RF Leakage Change	TVT RFI	0.00 1-00 1-00 1-00 1-00 1-00 1-00 1-00	AGC Ampl. Oscillation	600 kHz SCO
\tag{\tau}{\tau}	New VOC's installed in second retro- fit	Installed in first retrofit*	Installed in first retrofit*	Incorporated as part of retrofit	Not in- cluded	ans table and	Installed as part of first retro-	Installed Installed as part of first retrofits fit
S/II 2	OK as delivered	Installed in first retrofit*	Modified in first retrofit	Incorporated as part of retrofit	Returned to vendor & fixed*	Shipped & installed at KSC	OK as delivered	Shipped & installed at KSC
S/M 3	OK as delivered	Shipped and installed at MSFC	Modified in first retrofit	Incorporated as part of retrofit	Not included	OX as delivered	OK as delivered	OK as delivered
s/w s	OK as delivered	OK as delivered	Modified in first retrofit	Incorporated as part of retrofit**	OK as delivered	OK as delivered	OK as delivered	OK as delivered
37%	CK as delivered	OK as delivered	OK as delivered	Incorporated as part of retrofit**	Not included	OK as delivered	OK as delivered	OK as delivered

Was installed in first retrofit program. ** VAS mode leakage only, all other leakage change incorporated prior to shipment. *Shipped to MSFC or KSC, as required.

Table II-1. Test Set Status

2.3 SIGNIFICANT TECHNICAL ACHIEVEMENTS

A considerable amount of effort was expended in assuring that the Test Set would meet all of the technical objectives, namely: (1) Meet specifications as called out in the Work Statement, (2) Provide capability for completely evaluating the CCS Transponder, (3) Provide an accurate simulation of the MSFN Ground Station, and (4) Provide a flexible switching arrangement so that tests may be conducted accurately with a minimum of set up time. The following is a more detailed discussion of the significant technical achievements.

2.3.1 MSFN Simulation

Because the Test Set is designed to test a transponder that is to be compatible with NASA's Manned Space Flight Network, an early ground rule was established that this Test Set simulate the MSFN Ground Station equipment as much as possible. Motorola has built <u>all</u> of the types of equipment so represented in the MSFN. The Test Set, then, is essentially, identical to the MSFN equipment. Similarities/differences are as follows:

- a. Transmitter: The same electrical characteristics as represented in the MSFN Receiver-Exciter-Ranging Subsystem that Motorola has built for NASA.
- b. Test Receiver: The same electrical characteristics (in many cases, the exact same modules) that Motorola has made for NASA. The only exceptions were that the crystal filter in the IF Amplifier was changed to reduce the "pushing effect" (false lock), and a low noise parametric amplifier was not included.
- c. The 70 kHz Subcarrier Oscillator and the 1.024 MHz PCM Demodulator has the same electrical characteristics as the MSFN.
- d. The 70 kHz Demodulator and 1.024 MHz Modulator, which are used to check the Test Set 70 kHz Subcarrier Oscillator and the 1.024 MHz PCM Demodulator, have characteristics similar to those in the CCS Transponder.

e. The Ranging Codes are the same as that used by the MSFN. The Ranging Subsystem itself, however, is different from that used in the MSFN System because the MSFN Ranging Subsystem was not designed to check transponders. (See para. 2.3.3)

2.3.2 RF Leakage, Isolation, and RF Path Accuracy

It was a requirement of the Test Set that the r-f path be accurate to within ±2 db as a requirement, and to within ±1 db as a design goal, over the full range of 170 db, smoothly continuous. The steps that had to be taken to meet these requirements were as follows:

- Extremely accurate, continuously variable r-f attenuators were necessary, with some sort of redundancy, to give the user a confidence in the attenuator accuracy.
- 2. Switchable attenuators could not be used to increase the range from 120 db to 170 db, so a continuously variable attenuator, calibrated in 10 db steps, was necessary.
- 3. To meet the additional requirement of high power out of the Transmitter drawer for certain modes, it was necessary to use a variable
 attenuator with low insertion loss.
- 4. To allow the Test Receiver to operate as a threshold receiver without switching the variable attenuator out of the circuit, an attenuator with low insertion loss was required.
- 5. In order to meet the r-f path accuracy, and minimize interference from one mode to another, it was necessary to keep the r-f leakage to an extremely low value.

To meet the requirements of the above, the following designs were incorporated:

1. Two Marda Type 784 variable attenuators were used, one in the Test Receiver and one in the Test Transmitter. They were calibrated by Marda, traceable to the National Bureau of Standards, at the

appropriate frequencies of 2101 or 2282 MHz. They were also spot-checked by Motorola's Test Equipment Lab and were in full agreement. In the SELF TEST mode, one attenuator could be "played" against the other attenuator, to give the operator a measure of comparative accuracies of the two attenuators.

- 2. The "step" attenuator in the Test Transmitter consisted of a PRD

 198 variable attenuator, calibrated in 10 db steps. This attenuator
 is used in the SELF TEST and BENCH modes. Calibration of this attenuator
 is performed by comparing its attenuation to that of the Narda 784
 in the Transmitter.
- 3. & 4. The Narda attenuator described above has an insertion loss of less than I db. Thus, the power out of the Test Transmitter drawer was typically +12 dbm maximum, while requiring only +17 dbm out of the X24 Multiplier. For the Test Receiver, the noise figure at the input to the Test Receiver drawer (Part I) was degraded by only 1.7 db typically over that measured at the preselector input, typically 8.5 db.
 - 5. RF leakage and interference presented possibly the most challenging problems of the CCS Test Set. Some of the techniques that were used to solve these problems were as follows:
 - a. S-band r-f components were placed within a homogeneous aluminum box, made so by dip brazing the entire box.
 - b. The top and bottom covers of the r-f boxes were gasketed with a double-layer of r-f gasketing; many screws were used to keep even pressure on the gasketing.
 - c. Everything (except S-band) entering or leaving the r-f boxes
 was filtered with suitable r-f filters, in the case of signals,

or controlled by non-conducting rods through tubes that represent a waveguide beyond cutoff. These tubes were welded to the appropriate wall.

- d. Separate compartments were used when a large amount of isolation was required for a particular item. The Narda attenuators, for instance, were placed in their own compartment, with one connector of the attenuator protruding through the wall, and r-f gasketed so leakage would not occur around the attenuator.
- e. Solid shielded coax cable was used where it was necessary to reduce the S-band leakage through the wall of the coax, such as to another coax or a "hot" item.
- f. To achieve high isolation between different modes, coax relays with 70 db isolation (at S-band) were used. However, the relays used had poor isolation from coax to out of the relay (50 db or more), so in some cases, it was necessary to relocate some of these relays.

2.3.3 Ranging Subsystem (Delay Measurement)

The sophisticated ranging subsystem represents a significant technical achievement because of its accuracy, range of operation, and ease of operation. This subsystem is essentially a second generation of the ranging subsystem that Motorola developed for the Apollo Block II Special Test Equipment. Some of the salient aspects of this ranging subsystem are as follows:

- 1. It develops the same ranging codes that the MSFN ground station will use for actual flight.
- 2. The accuracy of measuring the transponder delay is exceptionally high for all modes and types of operation. To achieve this accuracy, it was necessary to eliminate all VCO's in the Ranging Receiver, which give an inherent, change in delay for a loop atress.

- 3. Have of operation of the ranging subsystem, to the point of being fool-proof, was a prime requirement of the ranging subsystem. This is particularly true in the automatic modes. Flexibility was required also, so the ranging subsystem may be operated in any one or all of the manual modes. These automatic/manual modes are:
 - a. Gain control to compensate for different modulation combinations and signal levels into the Transponder Receiver.
 - b. Acquisition of the PN codes.
 - c. Ranging delay measurements.

2.3.4 Ease of Operation

Of paramount importance in the design of the CCS Test Set was ease of operation. All functions that are necessary to monitor are immediately available at one or more monitor points merely by pushing a pushbutton, which gives the name of the function to be monitored (these functions are shown on the Test Set Block Diagram). No patching of cables is necessary. Yet, flexibility is maintained by providing pushbuttons, complete with relays, for additional functions that may be added later. Additional flexibility is accomplished by allowing additional equipment to monitor these selected functions merely by placing the additional test equipment across the input to one of the built in test equipment. Thus, all normal functions are displayed on oscilloscopes, a spectrum analyzer, and/or a wave analyzer for maximum visual display of electrical functions. In most instances, there is redundant measurement techniques allowed; such as, frequency using a counter or a scope, voltage using a scope, RMS VTVM, wave analyzer, etc. Other techniques, such as momentary pushbuttons and colored indicator lights for specific reasons, show that the Test Set was "human engineered" for minimum operator problems.

2.3.5 Long Term Stability

Trice on MDFC's list of requirements was good, long term stability. This Test Set was designed to be stable by the use of inherently stable circuits,

oven-controlled components and even subassemblies, and high negative feedbacks, where necessary. In addition, critical subassemblies were checked for drift and proper operation over the temperature range from 0°C to +55°C. The acceptance tests included a long term stability test (10 hours) on 9 separate parameters to prove the stability of each Test Set.

2.3.6 Radio Frequency Interference

Since the CCS Test Set was to be used at Kennedy Space Center, it was necessary that the Test Set not emanate interferring signals. Therefore, the Test Set was designed to suppress or contain interferring signals. The entire Test Set was tested to the radiated and conducted interference limits of MIL-I-6181D, with only two failures on the initial tests. Both of these failures were fixed. One failure was due to a piece of purchased equipment that did not meet Motorola's RFI requirements, and was subsequently fixed by the vendor. The other failure was a minor failure that was brought within specification limits by proper termination.

SECTION III

3.0 SYSTEM DESCRIPTION

3.1 GENERAL

The Command and Communications Test Set consists of four standard racks of drawers, designed and built by Motorola, Inc., off-the-shelf (commercial) test equipment, and power supplies. Circuit breakers are provided in each rack.

3.2 PURPOSE

The purpose of this Test Set is to check out the Command and Communications
Transponder in four different situations. These four situations or modes of
operation for the Test Set are BENCH XPNDR, BENCH PA, VAB, and PAD modes. A
SELF TEST mode for the Test Set is also provided.

In BENCH XPNDR and BENCH PA modes, the transponder and PA are mounted in the drawer provided in the Test Set. In the VAB, the Test Set is connected to the transponder by long cables and in the PAD mode the Test Set TWT Amplifier is put in operation and an air-link is used to the transponder. (Antennas are not provided.)

3.3 FUNCTIONS

Functionally, the Test Set transmits a precisely controlled S-band r-f signal, with various subcarriers and modulation, to the transponder under test, receives the S-band r-f signal reply from the transponder and demodulates the various subcarriers and modulation. In the process, it evaluates a number of transponder parameters. The Test Set provides the following functions:

- a. Four modes of operation, BENCH XPNDR, BENCH PA, VAB or PAD, and DELF TEST.
- b. Transponder and PA Mount drawer for the units under test and power for them.
- c. A stable S-band PM Test Transmitter.

- d. A phase-coherent S-Band Receiver Subsystem.
- e. A phase-coherent Ranging Subsystem.
- f. A Demodulator for recovering subcarriers and the information from the Test Receiver.
- g. A means of measuring power output and modulation characteristics of the Transponder Transmitter.
- h. A Transponder and Power Amplifier Control Panel for monitoring and controlling the power to and telemetry from the transponder.
- i. A TwT Power Amplifier to obtain an additional 10 watts through an external antenna to form an air-link between the Test Set and the transponder in the PAD mode.

3.4 TRANSPONDER TEST SET CAPABILITIES

In the BENCH XPNDR and BENCH PA modes, the tests in the following list may be performed on the transponder.

- a. Receiver center frequency
- b. Receiver tracking range
- c. Receiver tracking rate capability and acquisition capability
- d. Threshold sensitivity
- e. Receiver tracking loop bandwidth
- f. Receiver AGC voltage versus input signal level
- g. Receiver SPE voltage versus input frequency
- h. Receiver 70 kHz subcarrier demodulation
 - 1. Sensitivity
 - 2. Signal-to-noise ratio at output
 - 3. Frequency response
 - h. Phase response (delay change versus modulating frequency)

The following transponder (downlink) transmitter parameters can be tested with or without the power amplifier, and in either the voltage controlled oscillator (VCO) or the auxiliary oscillator (aux. osc.) mode.

- a. Transmitter frequency
- b. Transmitter power output
- c. Transmitter spurious outputs
- d. Transmitter phase noise
- e. 1.024 MHz subcarrier oscillator and bi-phase modulator performance:
 - 1. Subcarrier frequency (and frequency stability)
 - 2. Subcarrier modulation index
 - 3. Bi-phase modulator input sensitivity
 - 4. Subcarrier spectrum and carrier suppression
 - 5. Predetection signal-to-noise ratio
 - 6. Post-detection signal-to-noise ratio

In the VAB mode, transponder tests which can be performed are:

- a. Acquisition
- b. Tracking capability
- c. Threshold sensitivity
- d. Transmitter frequency (aux. osc.)
- e. Range delay
- f. 70 kHz subcarrier performance
- g. 1.024 MHz subcarrier frequency, frequency stability, and predetection signal-to-noise ratio

In the PAD mode, the same tests can be performed as in the VAB mode by use of the Test Set TWT Power Amplifier and appropriate antenna considerations (not supplied).

3.5 TEST SET FUNCTIONAL BLOCKS

The Test Set consists of a number of separate subsystems as follows:

3.5.1 Test Transmitter

The Test Transmitter function is entirely contained in one r-f tight drawer.

It generates a phase-stable S-band carrier capable of being phase modulated.

3.5.2 Modulation Control

The Modulation Control is packaged in one drawer and provides (1) the 70 kHz and 1.024 MHz subcarriers, (2) a square wave for modulating the 1.024 MHz subcarrier, and (3) modulation interfaces between external input, PN code input, etc. and the phase modulator located in the Test Transmitter. The sweep and decay circuitry and transmitter VCO control are also located in this drawer.

3.5.3 Test Receiver

The Test Receiver Subsystem consists of three drawers: A Receiver Control drawer, an r-f tight receiver front end drawer, and a drawer containing the remaining receiver modules. This receiver has essentially the same characteristics as the MSFN receiver that is expected to receive S-band signals from the CCS Transponder in flight.

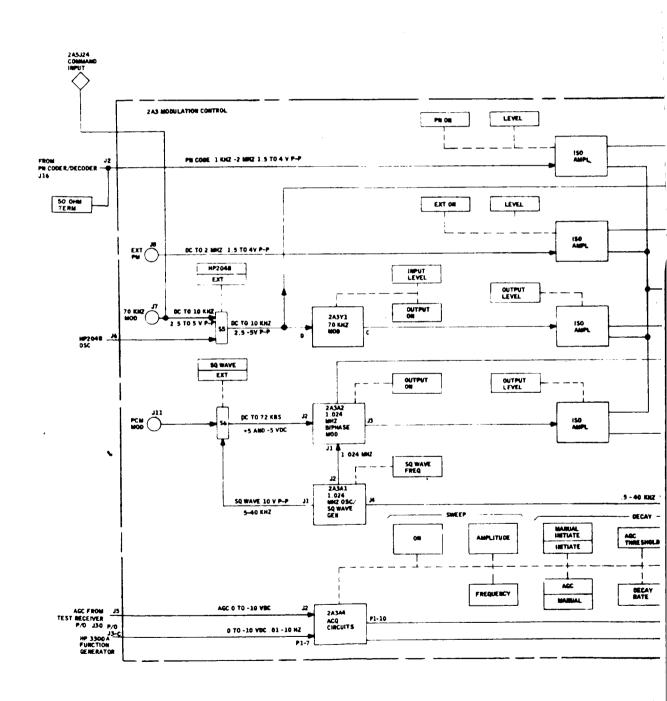
3.5.4 Demodulator

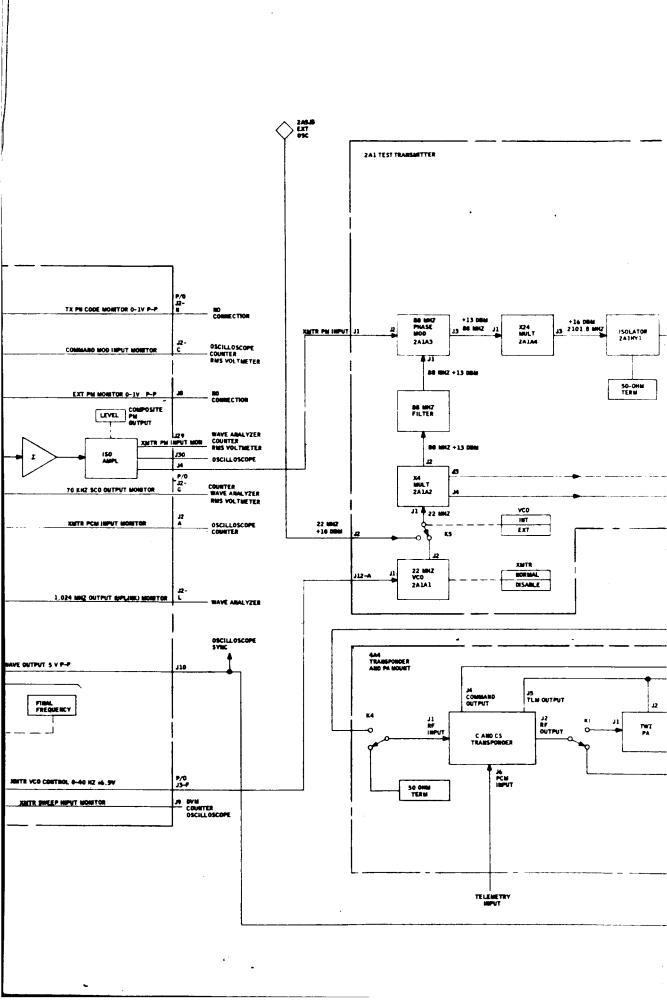
This subsystem is contained in one drawer and provides the capability of demodulating the subcarriers from the transponder signal and also demodulating the information off of the subcarriers.

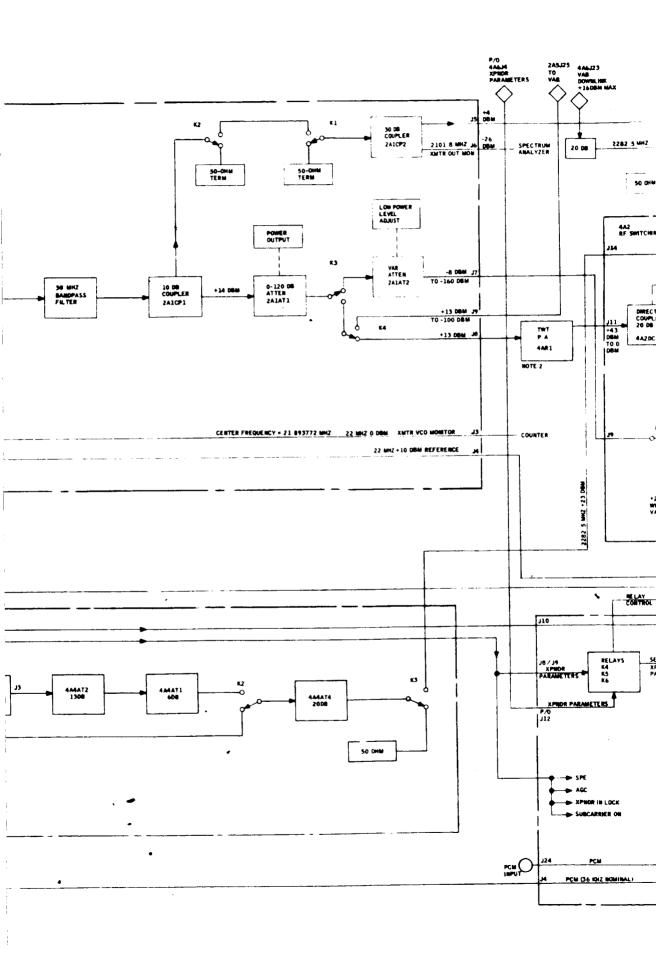
The 1.024 MHz PCM Demodulator and the wideband PM Demodulator operate in a manner similar to the MSFN System. The 70 kHz Demodulator has characteristics similar to the 70 kHz Demodulator in the CCS Transponder.

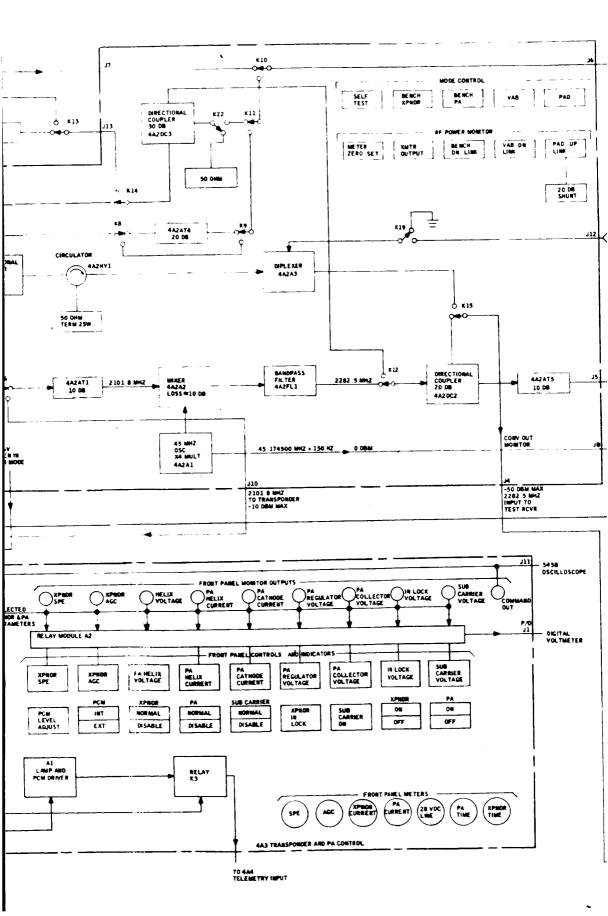
3.5.5 Ranging Subsystem

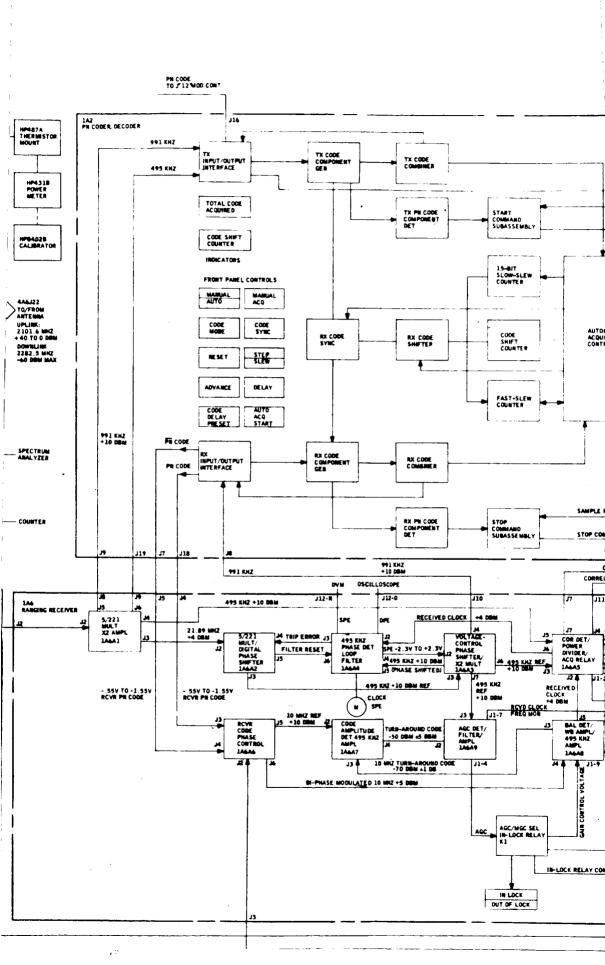
The Ranging Subsystem is made up of three drawers. The Ranging Receiver and time interval counter were designed to allow an operator to accurately test a CCS

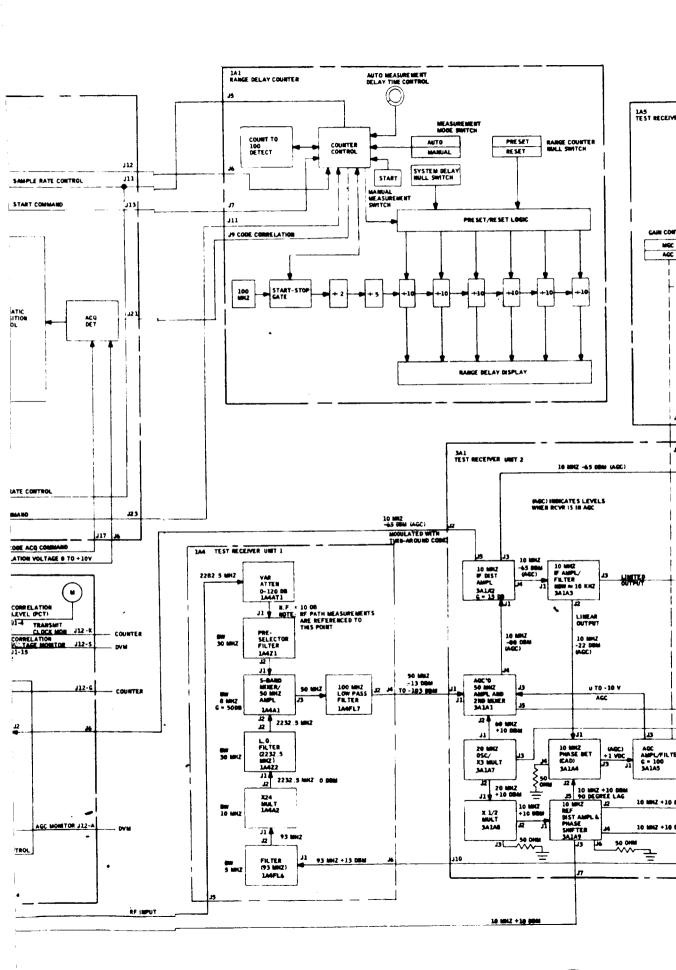


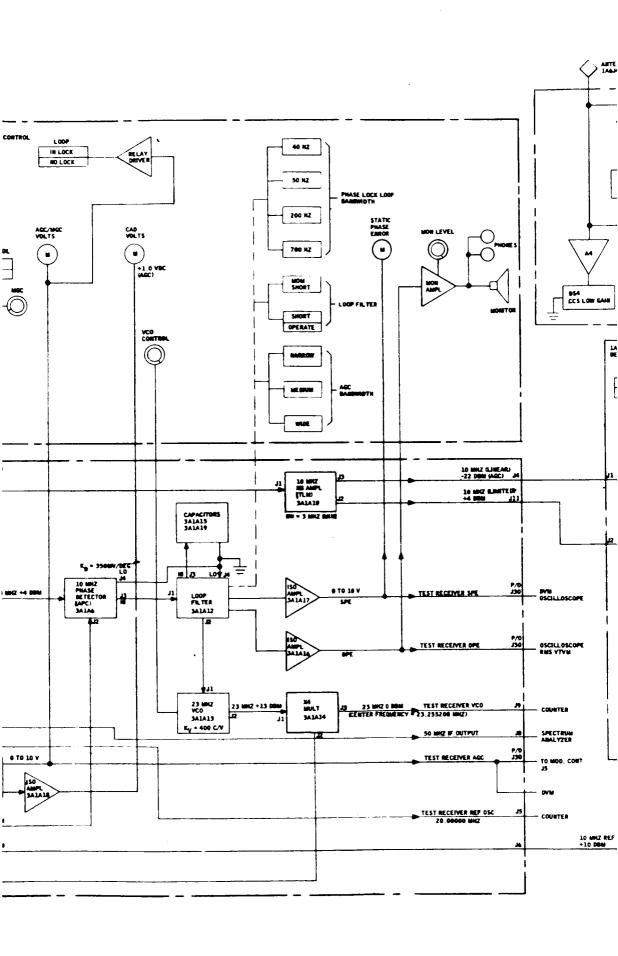


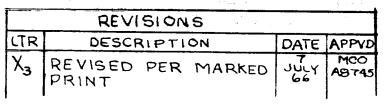












MA STATUS

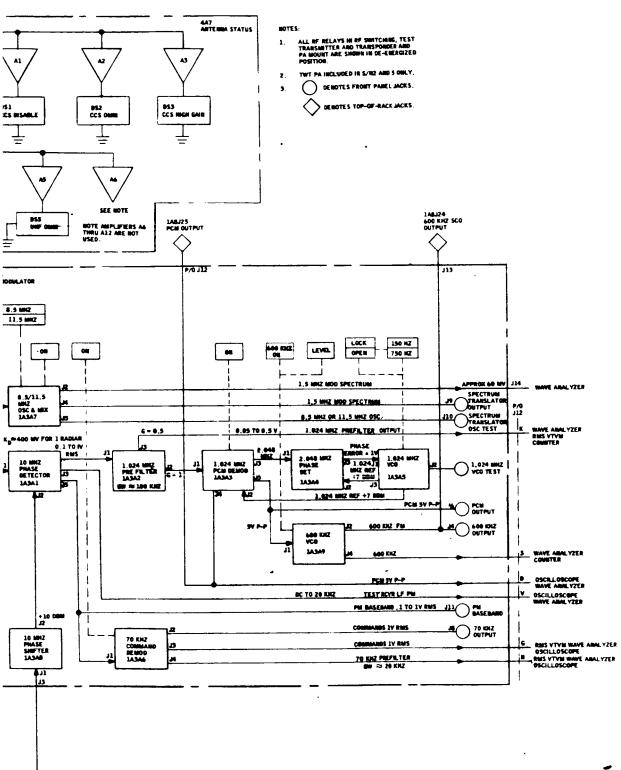


Figure 3-1. Command and Communication System Test Set, Block Diagram

Transponder and consequently their accuracy exceeds that of the transponder.

The PN Coder/Decoder develops the necessary code and decode functions to enable the ranging function.

3.5.6 RF Switching Drawer

The RF Switching Subsystem is contained in an r-f tight drawer. It selects the mode of operation of the Test Set, determines the inputs to r-f power monitoring equipments and the Test Receiver. This unit also contains the r-f converter function used in SELF TEST.

3.5.7 Switching Drawers

The Switching I drawer is an interface panel for connecting signals to the RMS Voltmeter, Wave Analyzer, and Frequency Counter. Switching II drawer is an interface panel for connecting signals to the Spectrum Analyzer, 561A Oscilloscope, and the 545B Oscilloscope. Switching III drawer is an interface panel for connecting voltages to the Digital Voltmeter.

3.6 TEST SET ELECTRICAL CHARACTERISTICS

Cha	rac	ter	istic	

Description

Test Set Power Requirement

Type

110-120 VAC, 60 Hz, single phase

Power Input

Approx. 30 amps

Test Transmitter/Test Receiver Characteristics

Phase Jitter

7° rms maximum in a 40 Hz loop

RF Path Accuracy

±2 db maximum, ±1 db design goal

Test Receiver Subsystem Characteristics

System Inputs

Center Frequency

Coherent Tuning Range

Non-coherent Tuning Range

Signal Level (nominal)

Variable Attenuator Range

2282.5 MHz

±244 kHz (using internal VCO)

2270 to 2280 MHz (using an external V00)

-60 to -150 dbm (at preselector input)

0 to 120 db

Test Receiver Subsystem Internal Characteristics

Voltage Controlled Oscillator

Center Frequency

Tuning Capability

VCO Sensitivity (Kv)

Long Term Stability

Predetection Filter

-3 db bandwidth

Noise bandwidth

23.255208 MHz

±244 kHz minimum (at S-band about center frequency

Approx. 400 Hz/volt

Approx. $1 \times 10^{-6}/10$ hours

6.3 kliz nominal

10 kHz nominal

Automatic Phase Control Loops and Thresholds

Type

Strong Signal Bandwidths

Adaptive, passive

40 Hz nominal

Threshold Bandwidths

50 Hz

200 Hz

700 Hz

-145.5 dbm

Level

-139.4 dbm

-133.4 dbm

Strong Signal Loop Gain

Weak Signal Noise Figure

Reference Oscillator

Frequency

Visual and Aural Aids to Lock

Aural

Visual

Approx. 5×10^6

10 db max. (referenced to preselector input)

20 MHz ±20 Hz

Speaker/Headphones to DPE

- 1. Oscilloscope on DPE
- 2. Panel meter and digital VTVM indications of SPE, CAD, and AGC
- 3. Lamp Indicator (from ACC/MCC)

Doppler Tracking Rate

Threshold BW 2BLO	Phase Erro (degree pea	
50 - 20	30	1,500
200 + 0 4	30	12,000
700 ⁺²⁰ / ₅	30	115,000
AGC Characteristics		
AGC	. 4	
Bandwidth Position	Time-Consta	
Narrow	150	0.16 ±0.04
Medium	15	1.6 ±0.14
Wide	4.0	6.0 ±1.5
RF Signal Level Dynamic Rang	e	-60 to -150 dbm minimum
Static Gain Stability (as strong signal)		0.4 db max/10 hours
MGC Control Range		-60 to -150 dbm minimum
Receiver Subsystem Outputs		
10 MHz IF Signal to Ranging Re	ceiver	
Level		-65 ±3 dbm (with AGC operating)
Bandwidth		±5.5 MHz minimum ±8 MHz
10 MHz Reference to Ranging Re	ceiver	
Level		+10 dbm ±3 db
10 MHz IF Signal to Demodulato	r , ,	
Level (limited channel)		+4 dbm nominal
Level (linear channel)	<i>:</i> `	-32 dbm to +8 dbm

AGC/MGC	Voltage	(to	Modulation	Control	Drawer')
---------	---------	-----	------------	---------	---------	---

Level

0 to -10 volts

Monitor Outputs

20 MHz Reference Oscillator

Frequency

Level

VCO Monitor

Frequency

Level

50 MHz Spectrum

Frequency

Level

AGC/MGC Voltage Level

Demodulator Drawer Characteristics

Inputs

10 MHz Phase Detector Input (signal)

10 MHz Phase Detector Input (reference)

10 MHz Spectrum Input

Input Bandwidth

70 kHz Subcarrier on 10 MHz

Type of Modulation on 10 MHz

Type of Modulation on 70 kHz

1.024 MHz Subcarrier on 10 MHz

Type of Modulation on 10 MHz

Type of Modulation on 1.024 MHz

20 MHz

+1.5 dbm ±1.5 db

23 MHz nominal

 $0 \pm 3 \text{ dbm}$

50 MHz nominal

40 db above input signal level (nominal)

0 to -10 volts

+4 dbm ±1 db

+10 dbm ±3 db

-22 dbm nominal

-12 dbm max. for linear operation

3 MHz minimum

Phase

Frequency

Phase

Bi-phase

Demodulator Drawer Internal Characteristics

10 MHz Detector

Type

Output Level (W.B.)

DC Bandwidth (W.B.)

70 kHz Demodulator

Type

Carrier Frequency

Predetection -3 db Bandwidth

Input Level

1.024 MHz Demodulator

Type

Predetection -3 db Bandwidth

Carrier Frequency

Maximum Information Rate

Loop Bandwidth, 2B_I

Spectrum Translator

Input Level for Linear Output

Phase

(Kd) x (Sine of Mod. Index) where Kd is approx. 10 mv/o

DC to 1.5 MHz

FM (Pulse-counting)

70 ±1 kHz

20 ±5 kHz

0.1 to 1.0 VRMS

PM with Phase-Lock Loop

160 kHz ±10%

1.024 MHz ±50 Hz

72 Kilobits/sec.

750 Hz, 150 Hz

-22 dbm maximum

Demodulator Drawer Outputs

10 MHz PM Demodulator

Wideband Output (Front Panel)

L.F. Output Bandwidth

70 KHz Pre-filter output level

70 KHz Demodulator Outputs

Number

Level (95 ohm load)

Bandwidth (-3 db)

Phase Linearity

10 MHz Prefilter output level.

1.024 MHz Demodulator Outputs (2)

Level

Frequency

Logic

VCO Test Level

Modulation Spectrum

Level

Bandwidth

600 KHz Modulator

Туре

Center Frequency

Deviation (by PCM)

Linear Range of Deviation

Output Level (into 950 ohms)

High Z Load only

100 Hz to 10 KHz

approx. 6 db below input

Two

1V RMS for 5 KHz peak dev.

100 Hz to 4 KHz minimum

700 - 4000 Hz, within $\pm 20 \mu \text{sec}$

300 - 700 Hz within $\pm 120 \mu \text{ sec}$

Approx. 6 db below input

5V p-p

Limited by Prefilter

Ambiguous

+4 dbm nominal

1 VRMS maximum

2 MHz minimum

FM by PCM Output

600 KHz

36 ± 6 KHz peak

to 54 KHz peak

1 VRMS to 2.5 VRMS

Modulation Control Drawer Characteristics

Drawer Inputs:

Command Modulation on 70 KHz

Level:

5V p-p maximum

Bandwidth:

DC to 10 KHz

PCM Modulation Input

Level:

10 V p-p nominal

Square Wave Generator

(internally generated)

Frequency (Front Panel Adjust):

50 Hz to 36 KHz minimum

PRN

Level:

4 V p-p maximum

Bandwidth (-3 db)

DC to 2 MHz

Sweep

Level:

15 V p-p maximum

Frequency

DC to 10 Hz

Drawer Outputs

Composite PM and Monitor

Output Level:

5V p-p maximum

Bandwidth:

DC to 2 MHz, minimum

VCO Control and Monitor

Level:

± 6.5 volts

Bandwidth:

DC to 10 Hz

Monitor Outputs

Circuits

PCM Input, command modulator
Input, 70 KHz SCO Output,
1.02h MHz modulator output,
sweep output

Sweep Drive (to HP 3300A)

Frequency (Front Panel Adjust)

0 to -10 VDC

(The input to the HP 3300A function generator is normally disconnected at the rear of the HP 3300A. This allows the HP 3300A dial only to control the frequency. When the frequency of the HP 3300A is to be remotely adjusted by the Modulation Control Drawer, remove shorting bar from rear terminals of the HP 3300A and attach cable 2W42 to the HP 3300A.

Transmitter Drawer Characteristics

Drawer Inputs:

Phase Modulator Input

Frequency

DC to 2.0 MHz

Modulation Capability

0 to 3 radians minimum

Frequency Modulator Input

Frequency (sweep rate)

O to 100 Hz minimum

Level

O to ± 6.5 V DC nominal

External Oscillator Input

Frequency

approx. 22 Miz, or 1/96

of output frequency

+10 dbm +6 - 0 db

Level

Drawer Outputs:

VCO Frequency Output (to counter)

Frequency

22 MHz approx. or

1/96 of S-Band output

frequency

Level

 $0 \text{ dbm} \pm 3 \text{ db}$

VCO Ranging Reference Output

Frequency

22 MHz approx., or 1/96

S-Band output

Level

 $10 \text{ dbm} \pm 3 \text{ db}$

S-Band Outputs

Nominal Frequency

2101.802 MHz (provided

by the internal VCO

Tuning Range

± 222 KHz minimum

about nominal center frequency

RF Bandwidth (external VCO)

Flat to within 1 db at ± 5 MHz

Residual AM

± 1 db maximum when phase

Modulated to 3 radians

Power Meter Output Level

+5 dbm ± 4 db

Spectrum Analyzer Output Level

-25 dbm \pm 5 db

RF Switching Drawer Low Level

Variable -8 dbm maximum to

-170 dbm minimum. Settable ± 1 db,

calibrated to within ± 2 db

Variable +13 dbm to -107 dbm

TWT Amplifier Output

RF Switching Drawer Characteristics

SELF TEST Mode:

Input signal (J9)

Frequency

Level

Output Signal #1 (J5)

Frequency

(Input signal frequency

Conversion Loss (with -10 dbm input)

Output Signal #2 (J4)

Output Signal #3 (J8)

Frequency

Level into 50 ohms

2101.8 MHz ±220 kHz

-10 to -160 dbm

2282.5 MHz nominal

+180.698 MHz)

36 db maximum

10 db below #1 output

45.174500 MHz ± 150 Hz

+10 dbm nominal

Bench Transponder Mode:

Input to output insertion losses at 2282.5 MHz

J9 to J10

J14 to J5

J14 to J4

2 db nominal

60 db nominal

70 db nominal

Bench Power Amplifier Mode:

Input to output insertion losses at 2282.5 Mlz

J9 to J10

O db nominal

J14 to J5

60 db nominal

JU; to Jl;

70 db nominal

VAB Mode:

Input to output insertion losses at 2282.5 MHz

J13 to J5

40 db

J13 to J4

50 db

PAD Mode:

Input to output insertion losses

Jll to Jl2

1.5 db max. at 2102 MHz

J12 to J4

1.0 db max. at 2282 MHz

Power Monitor Meter Zero Set

(Depress METER ZERO SET switch)

Input to output insertion losses at 2102 MHz

J7 to J6

2 db maximum

Power Monitor Transmitter Out

(Depress XMTR OUTPUT switch)

Input to output insertion losses at 2102 MHz

J7 to J6

0 db nominal

Power Monitor Bench Downlink

Bench Transponder RF power output

(Depress both BENCH XPNDR and BENCH DOWN LINK switches)

Input to output insertion at 2282 MHz

Jll to J6

2 db maximum

Power Monitor VAB Downlink

VAB downlink RF power

(Depress both VAB and VAB DOWNLINK switches)

Input to output insertion losses at 2282 MHz

J13 to J6

2 db maximum

Power Monitor Pad Uplink

PAD uplink RF power output

(Depress PAD UPLINK switch)

Input to output insertion losses at 2102 MHz

J11 to J6

41 db nominal

Ranging Subsystem

Type:

Code:

Code Acquisition Automatic

Uses a pseudo-random noise ranging code with direct delay readout in nanoseconds, for delay less than 1 millisecond, and readouts in bits and nanoseconds for longer delays.

A LUNAR code of 2,728,341 bits and a SATELLITE code of 35,805 bits - identical to the JPL Mark I Ranging Codes. Maximum unambiguous range of LUNAR Code; 513,000 miles.

Maximum unambiguous range of Range Delay Counter: 999,999 NS (approx. 100 miles)

- 1. Rate of search: 0.5 seconds per bit
- 2. Range of search: 15 bits over any preset range from 0 to 999 bits.
- 3. Indication of acquisition: automatic when correlation exceeds 62.5%.

Code Acquisition: Manual

Correlation Detection:

Resolution:

Accuracy:

Ranging Receiver

General Type:

Dynamic Range:

Clock Frequency Range:

Delay Stability:

- 1. Type of acquisition: full code or by sub-codes
- 2. Indication of acquisition: visual indication of correlation absolute level of correlation voltage in automatic mode, relative levels in manual mode.

± 1 nanosecond

Dependent on input signal (clock power) to noise ratio and the sampling period selected.

automatic phase lock
automatic gain control
static offset frequency (zero doppler)

Exceeds 40 db (PRN sideband power greater than -65 dbm to less than -105 dbm)

 $495.334 \text{ KHz} \pm 25 \text{ Hz}$

± 2 nanoseconds due to frequency offset 5 nanoseconds max. for PRN sideband power between -70 dbm and -100 dbm.

10 nanoseconds maximum for ambient temperature variation of $30^{\circ}\mathrm{F}$

AGC Loop Gain:

Clock Phase Tracking Loop Noise Bandwidth:

30 db/db minimum

2 Hz nominal

Transponder and PA Control Drawer Characteristics

No signals are generated within the Transponder and PA Control Drawer. One subassembly serves as a lamp driver and a single-ended to double-ended PCM driver. A second subassembly contains 10 relays for voltage monitoring. The power and telemetry signals controlled by this drawer provide operating power and monitor outputs for the Transponder and Power Amplifier under test.

Transponder and PA Mount Drawer Characteristics

No signals are enerated by the Transponder and PA Mount Drawer.

Switching I, II, and III Drawer Characteristics

The signals to be monitored on the three switching panels are selected by the individual pushbutton switches on each drawer. Each drawer contains several subassemblies containg 10 relays for voltage monitoring.

TWT Power Amplifier Characteristics

(Included only in Test Sets S/N 2 and 5)

Procurement specification

Saturated Power Output

Saturated Power Gain

Noise Figure

Center Frequency

Motorola No. 12-21510H, Issue X4

+43 dbm (20 watts)

+33 db minimum

+35 db maximum

2101.8 MHz

SECTION IV

4.0 ADDITIONAL TEST DATA

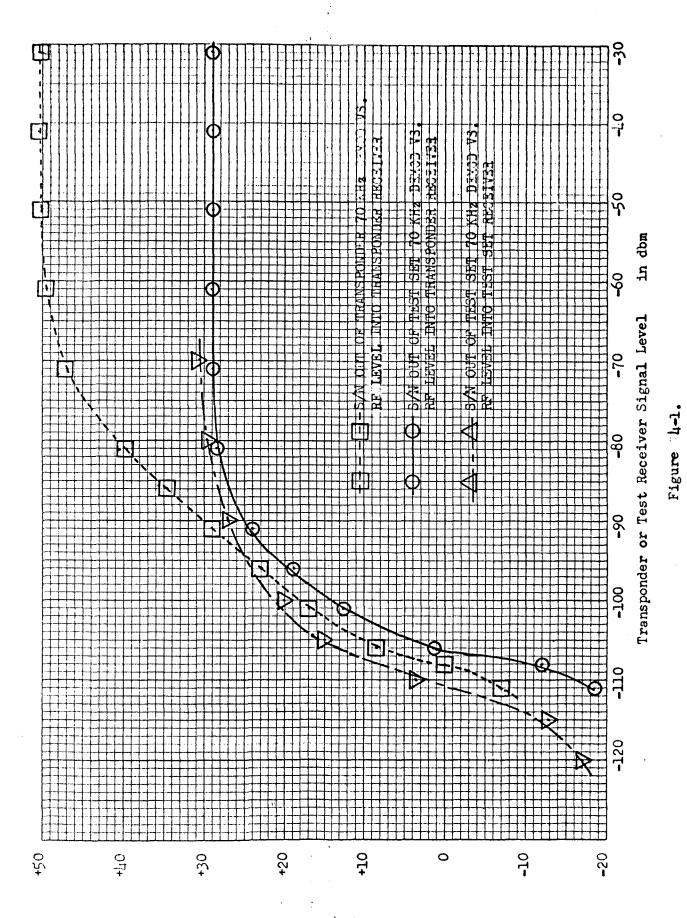
Many measurements were made on CCS Transponder S/N 2, using the CCS Test Set. Some of those tests were performed in the course of the acceptance tests performed on some or all of the Test Sets. Other tests were performed on one or more Test Sets, primarily to assure us that the Test Set would perform the functions of testing the transponder in an accurate manner. Some of the later set of tests (those not in normal acceptance tests on the Test Set) are described here.

4.1 SIGNAL-TO-NOISE RATIO OF 70 kHz DEMODULATOR

Figure 4-1 shows the signal-to-noise output of the 70 kHz Demodulator in the Test Set vs. signal level into the Test Receiver. This curve marked — — — and Table IV-lgive the pertinent parameters. (This data was taken from the acceptance tests on Test Set S/N 4.)

The curve marked — — — on Figure 4-1 is the signal-to-noise out of the 70 kHz (Command) Demodulator in the transponder. Note that this curve is approximately 2 db worse than that out of the Test Set 70 kHz Demodulator (at weak signals), which is the difference in noise figures of the two receivers. This proves that the Test Set 70 kHz Demodulator performs in a manner quantitatively similar to the Command Demodulator in the transponder.

The third curve of Figure 4-1 that is marked ——————, was taken in a different manner than normally done. The Test Transmitter was modulated with a 70 kHz subcarrier. This subcarrier was turned around in the transponder through the ranging channel, modulating the downlink with the 70 kHz signal and noise. The 70 kHz subcarrier was demodulated in the Test Receiver, and the signal-to-noise out of this demodulator was measured as the transponder receiver input signal was reduced. The downlink signal into the Test Receiver was kept



S/N Out of 70 KHz Demodulator Vs. Received Signal Level into Test Receiver or Transponder

strong (approximately -70 dbm). The explanation of why this curve did not agree identically with that out of the transponder 70 kHz demodulator is beyond the scope of this report.

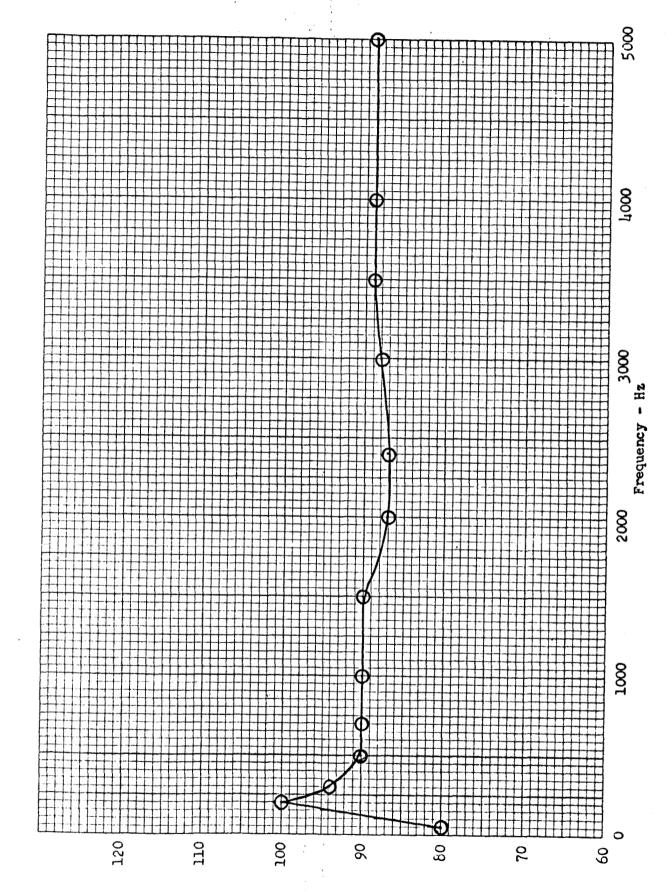
Table IV-1. Conditions for Figure 4-1.

Curve	Modulation on the 70 kHz Subcarrier	Demodulator Used	Transponder Noise Figure	Test Receiver Noise Figure	Modulation Index of 70 kHz
4-4-	2 kHz sine wave at	Test Set	N/A	8.5 db	1.2 radians peak
-00-	5 kHz peak deviation	Transponder	10.5 db	N/A	1.2 radians peak
-0) [Test Set	10.5 db	8.5 db	(1.2 radians peak up
					1.16 radians peak down

4.2 COMMAND CHANNEL PHASE RESPONSE

The Test Set 70 kHz Demodulator was designed to be essentially the same as the Command Demodulator in the transponder. There is one difference, however: the output filter in the Test Set 70 kHz Demodulator was designed to have flatter phase response than the corresponding filter in the transponder. This agreed with the philosophy that the Test Set should be the same electrically as the corresponding circuit in the transponder, but the test circuit should be quantitatively better so it can be used to test the transponder.

Phase response, or time delay, which is really the important parameter, was measured on all 70 kHz Demodulators as part of the drawer tests on the demodulator. The results of one of these is plotted on Figure 4-2.



Time Delay in Microseconds

Figure 4-2. Command Channel Time Delay

4.3 TRANSPONDER RANGING DELAY

Using the CCS Test Set, the ranging delay of a CCS Transponder can be easily determined. This was done on CCS Transponder S/N 2 using several Test Sets.

a. Ranging Delay as Uplink Signal Level is Changed

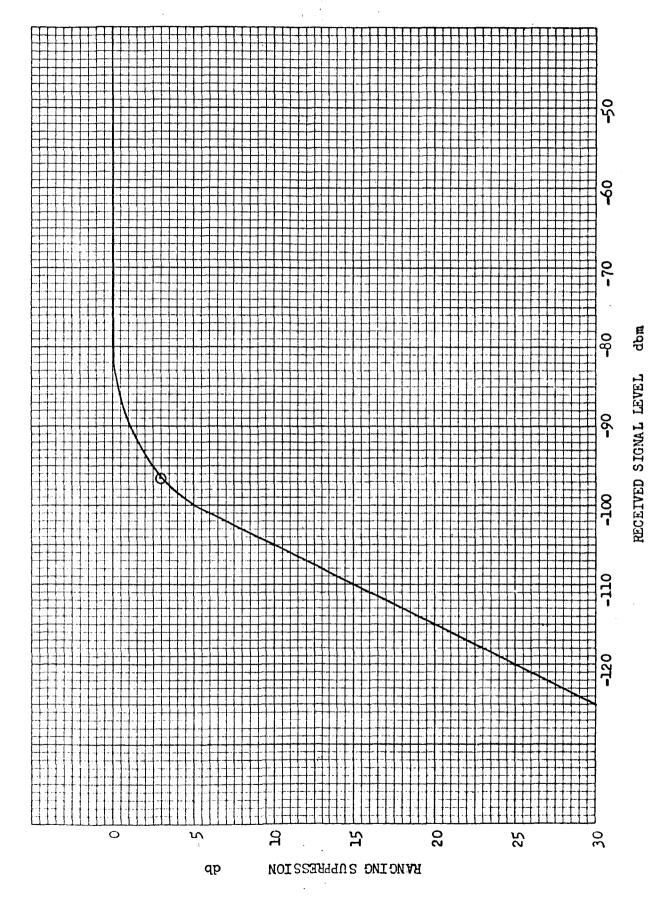
The transponder suppresses the turn-around ranging power (the ranging power into the ranging receiver) when the r-f signal into the transponder receiver is reduced. This effect is shown in Figure 4-3.

(See Reference 1.)

Because of this turn-around suppression, the ranging rcvr. is required to be able to operate over a wide ranging power. For this reason, a ranging delay vs. ranging power test is performed on each Test Set in the SELF TEST mode. These results are plotted on Figure 4-4 for three different Test Sets, but in a manner modified from the original data. Figure 4-4 converts "reduction in ranging power, in db" to "Received Signal Level into S/N 2 CCS Transponder, for 0.6 Radians Modulation on Uplink".

Part of each of these curves are due to the Ranging Receiver operating in noise, and part of the curve due to the method in which the test was conducted. For this test, the modulation index of the ranging was changed to simulate a reduction in ranging power on the downlink by the Transponder Receiver suppression. However, the modulation index was changed by adjusting a pot on the modulation control drawer. As the pot is adjusted, the upper frequency is changed, which changes the time delay. Our experience has been that the change in time

Reference 1. Pages 103-105, "Electronic Systems Test Program Final Report CCS Transponder/MSFN for Compatibility and Performance Evaluation", Information Systems Division, NASA, Manned Spacecraft Center. Report CB-66-3302-U, 15 April 1966.



RANGING SUPPRESSION OF CCS TRANSPONDER S/N 2

FIGURE 4-3.

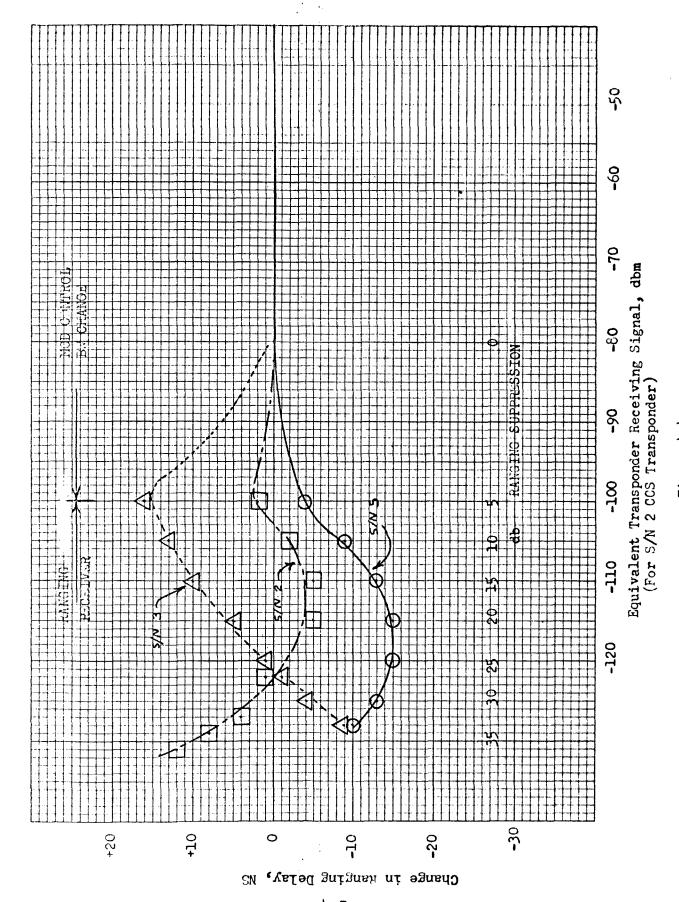


Figure 4-4. Change in Delay Due To CCS Test Set

delay due to the modulation control is greatest at higher levels of modulation (modulation index). Hence, only the part of the curves to the left (lower signal levels) of -100 dbm, represent the real time delay change in the Ranging Receiver due to change in ranging modulation. This part represents a correction to total ranging delay of a transponder when measured in Test Set S/N 2. Applying the above correction gives the ranging delay just due to the transponder itself. Both the correction for S/N 2 Test Set and the corrected curve are shown in Figure 4-5.

Figure 4-6 shows the change in ranging delay through CCS Transponder, S/N 2 using Test Set S/N 5. Also, the change in delay through the Test Set itself (in the SELF TEST mode) is shown, as the frequency is changed. Keep in mind that there is only 1 ns resolution, so these curves are not too accurate. However, they do show that the change in delay through S/N 2 Transponder and the delay through the CCS Test Set is insignificant. For comparison purposes, the change in system delay through the modified DSIF Receiver-Exciter-Ranging Subsystem (S/N 3) with Apollo Block I CSM Transponder S/N E-2 is shown, at least in part (See Reference 2). It is not fair to make a direct comparison of those two curves. The second curve is shown to illustrate the effect of VCO loops in the Ranging Receiver. This

Ranging Delay vs. Change in Carrier Frequency

Reference 2. "Task I - Final Report, Apollo Unified S-Band System Block I Compatibility Test Program", Motorola, Inc., Report WF 2996-23, 8 September 1965.

the Ranging Receiver.

shows the reason why this Test Set, designed to test a transponder,

is more accurate than other devices that use the VCO loop method in

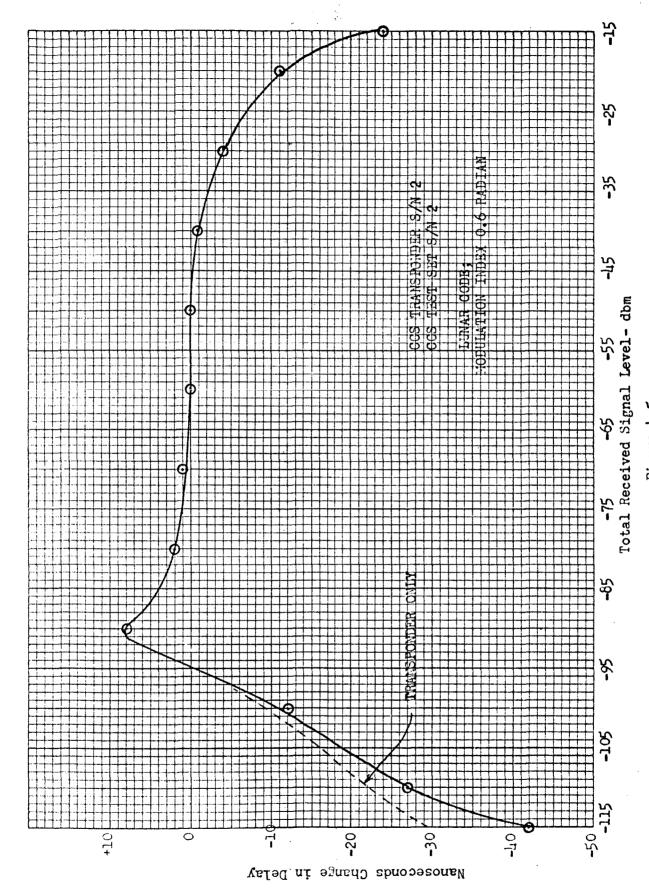


Figure 4-5. Change in Ranging Delay Vs. Transponder Input Signal Level

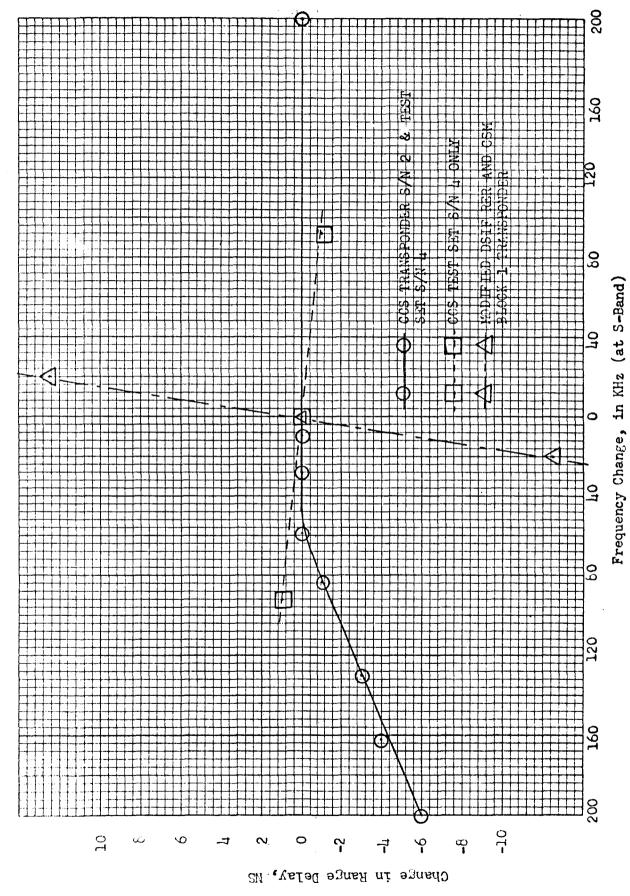


Figure 4-6. Range Delay Vs. Up-Link Offset Frequency

SECTION V

5.0 RECOMMENDATIONS

The CCS Test Set represents a complete Test Set that meets the objectives for which it was designed. There are several things that could be done to improve its usefulness for MSFC.

5.1 IMPROVED STRONG SIGNAL PERFORMANCE OF THE TEST RECEIVER

The strong signal performance of the Test Receiver, being the same as the DSIF and MSFN Receivers, is limited by the signal-to-noise out of the receiver. This signal-to-noise ratio is limited because of the gain distribution of the receiver. Figure 5-1 shows the signal and an estimate of the noise at certain points of the Test Receiver. Some of these are estimates, and indeed, the critical noise contributing stages are not specified. However, a study of this figure indicates why the strong signal signal-to-noise ratio is not better than it is.

Shown on Figure 5-1 are attenuators "X". These attenuators do not exist in the present Test Set Receivers, but could be added quite easily. Tables V-la and V-lb show the signal and noise at various points for X = 0 and for each X = 20 db, respectively. For the present Test Receiver, the output signal-to-noise ratio is -12 db for a noise bandwidth of 4 MHz, which is approximately the two-sided noise bandwidth of the PM output. For X = 20 db, this signal-to-noise increases to +8 db, for an improvement of 20 db.

There is a penalty one must pay for this strong signal improvement in signal-to-noise - the threshold performance of the test receiver may suffer. The receiver was designed to be used in the DSIF System of JPL, where thresholds of lower than -170 dbm were specified (using a traveling wave maser). At this signal level, the i-f amplifier must have 50 db gain for X = 0 and 70 db gain for X = 20 db. The AGC'd amplifier part of this module is not capable of 70 db

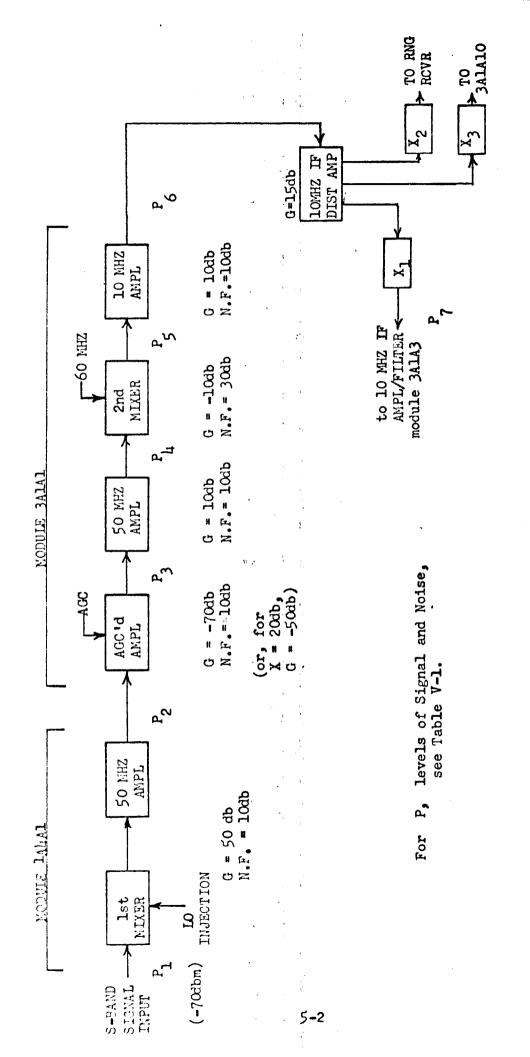


FIGURE 5-1.

gain. For the MSFN System, signal levels can go to about -158 dbm. For this Test Set, signals can go to about -150 dbm. The i-f amplifier probably has adequate gain for -150 dbm, if X = 20 db.

Signal levels at other parts of the Test Set will be incorrect if this 20 db pad is added. For instance, the level to the ranging will be -45 dbm, instead of the -65 dbm required. Also, the level to the 10 MHz narrowband amplifier, 3AlAlO, should also be reduced to -65 dbm. These corrections are made by adding X₂ and X₃, also 20 db.

5.2 MODIFICATIONS TO ALLOW MORE COMPLETE INVESTIGATION FOR COMMAND CHANNEL

The 70 kHz Demodulator in the Test Set, and that in the Transponder, can be quantitatively checked by measuring signal-to-noise output. This does not give a complete picture of the performance of the command channel, however, the method that MSFC has used was to correct the command decoder and measure message reject rate. With slight modification, the CCS Test Set could be made to measure subbit error rate and/or message reject rate. A scheme to do this is shown on Figure 5-2.

The blocks shown in solid lines on the right part of Figure 5-2 would be needed to determine sub-bit error rate (SBER). Errors would be counted on an events counter. (The HP-5245L, installed in the Test Sets, can be used without modification.)

Since the sub-bit rate is 1 kb/s, bits transmitted can be determined either with an events counter, or a watch. The detector should be identical electrically to that in the command demodulator.

The blocks shown in dashed lines represent that which would be added if message acceptance pulses (MAP) and message reject pulses are to be counted. Message reject rate is messages rejected per messages sent.

Table V-la
Signal and Noise Levels
CCS Test Receiver As Is

Symbol	<u>Point</u>	Sig. Level	N _A	N _B	NBW MHz	Total Noise Power dbm	S/N db
P ₁	S-Band Input	- 70		-164 (referred) to input)	10	-94	+214
P ₂	Input to AGC'd Amp	- 20		-114	10	-111	+24
P ₃	Output of AGC'd amp	- 90	-184	-164	10	-94	+14
P_{l_4}	Input to Mixer	- 80	-154	-164	10	-84	+11
P ₅	Output of Mixer	- 90	-164	-144	10	-74	-16
P6	10 MHz Output	- 80	-134	-164	10	-64	-16
P ₆	10 MHz Output	-80	-134	-164	4	- 68	-12
P ₇	Input to 10 MHz Amp/Filter	- 65	-119	-164	4	- 53	-12

Table V-lb Signal and Noise Levels CCS Test Receiver with X_1 , X_2 , and X_3 = 20 db

Symbol	<u>Point</u>	Sig. Level	N _A	N _B	NBW MHz	Total Noise Power dbm	S/N db
Pl	S-Band Input	-70		-164 (referred to input)	10	-94	+24
P ₂	Input to AGC d Amp	- 20		-114	10	-24	+51
P ₃	Output of AGC'd Amp	- 70	-164	-164	10	-91	+21
P_{4}	Input to Mixer	- 60	- 151	-164	10	-81	+21
P ₅	Output of Mixer	- 70	-161	-144	10	-74	+14
δ^{q}	10 MHz Output	- 60	-134	-164	10	-614	+1.
PG	10 MHz Output	- 60	-134	-164	4	-68	+8
P7	Input to 10 MHz	-65	-1 39	-16/4	4	- 73	+8

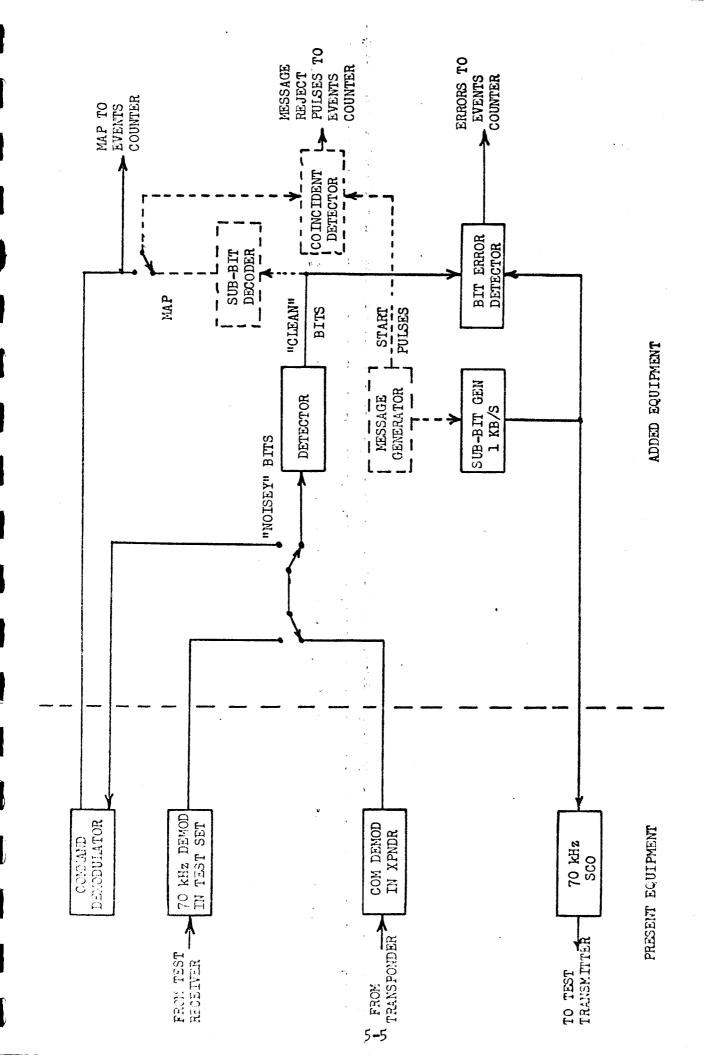


Figure 5-2. Modifications for Command Channel Investigation

If improvements to either the command demodulator or the sub-bit demodulator are to be made, then this scheme or an equivalent is necessary. Also, this scheme will allow a more complete checkout of the command system.

5.3 RANGING SELF-CHECK FEATURE

After the Ranging Subsystem was designed, and during the system check-out, a very useful test was performed on the Range Delay Counter and PN Coder/Decoder. This test consisted of a Self-check of these two drawers. The purpose of this set of tests is as follows:

- Give confidence that the Range Delay Counter and PN Coder/Decoder are working properly.
- 2. Greatly simplifies troubleshooting of the Ranging Subsystem.

It is recommended that the PN Coder/Decoder and the Range Delay Counter be modified as described below.

This retrofit will require the addition of a FC card in the Coder Bay assembly, a 1 MHz amplifier in the Range Delay Counter, three coax relays in the coder and associated bay, drawer and drawer interface wiring. The SELF TEST logic is shown in Figure 5-3. A normal-test switch will be added to the rear bulkhead of the Coder. This switch, when set in the test mode, will enable three coax relays which in turn switch the Coder's T_X C_L, R_X C_L and C_L inputs from the ranging receiver to the internal clock generator. The normal-test switch will also enable a correlation-voltage generator and a test indicator light when the switch is set to the test mode. The Coder's auto acquisition start switch-light will be converted into a start switch-light and self-test indicator. The self-test indicator will be enabled when the Coder/Range Delay Counter is operating in the self-test mode. The total code acquired light will be converted into a switch-light. The switch will (enabled during self-test) select either a 25% or 100% correlation level.

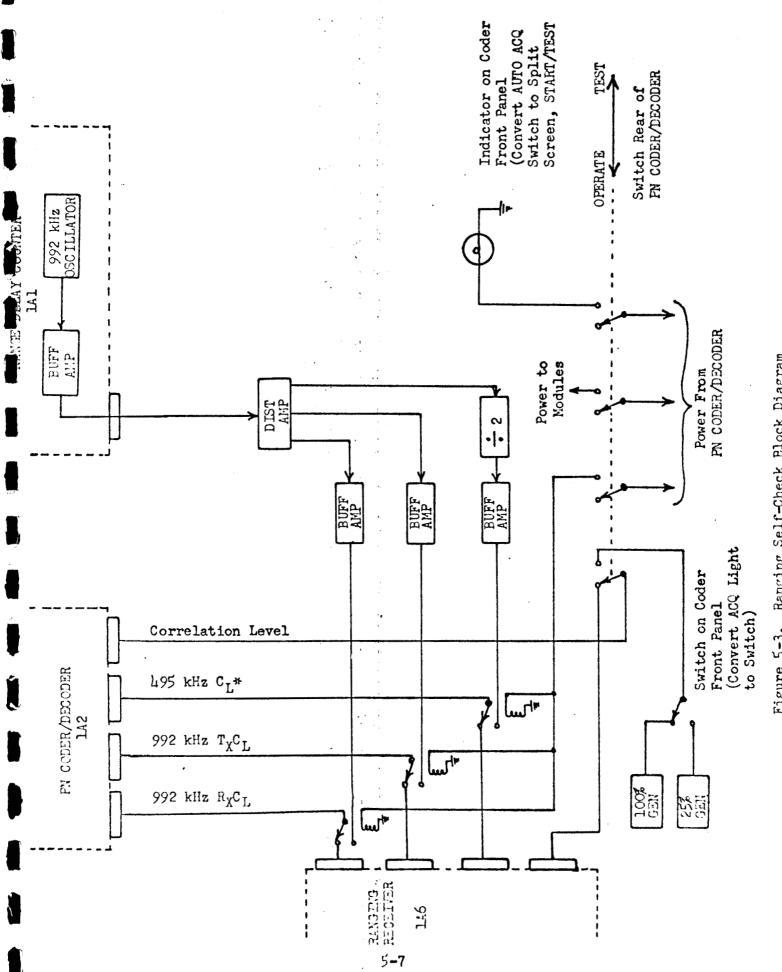


Figure 5-3. Ranging Self-Check Block Diagram

The operator may set the Coder and Range Delay Counter in the self-test mode by:

- 1. Set the MANUAL-TEST switch to TEST.
- 2. The digital system is now ready for self-test operation and it is suggested that the operator follow the Coder/Range Delay Counter self-test procedure outlined in the operational manual.

5.4 PCM BIT ERROR DETECTOR

The performance of the 1.024 MHz Bi-Phase PCM Modulator in the transponder can best be determined quantitatively by measuring the bit-error rate under various conditions. For more complete tests, then, it is recommended that a message generator, bit synchronizer, and bit-error detector be used. The CCS Test Set can be easily modified to allow the addition of this equipment. An example of how it could be set up is shown in Figure 5-4.

5.5 DYNAMIC RANGING SUBSYSTEM AND DYNAMIC RANGE AND DOPPLER SIMULATOR

The present Ranging Subsystem was designed to test transponders. As such, it was not designed to be used with a changing (dynamic) range or doppler. For experimental purposes, it might be desirable to have this capability.

Modifications to the present CCS Test Set that would allow this, are as follows:

- 1. Substitution of a VCO loop for the automatic phase control loop in the Ranging Receiver.
- 2. The addition of a code clock transfer loop to the Ranging Receiver.
- 3. The addition of a dynamic r-f doppler unit.
- 4. The addition of a dynamic ranging unit. This unit should also allow the presetting of any "Start" range.

The first two items are relatively straight foreward, and could be accomplished by the addition/change of several modules in the ranging drawer. A switch could

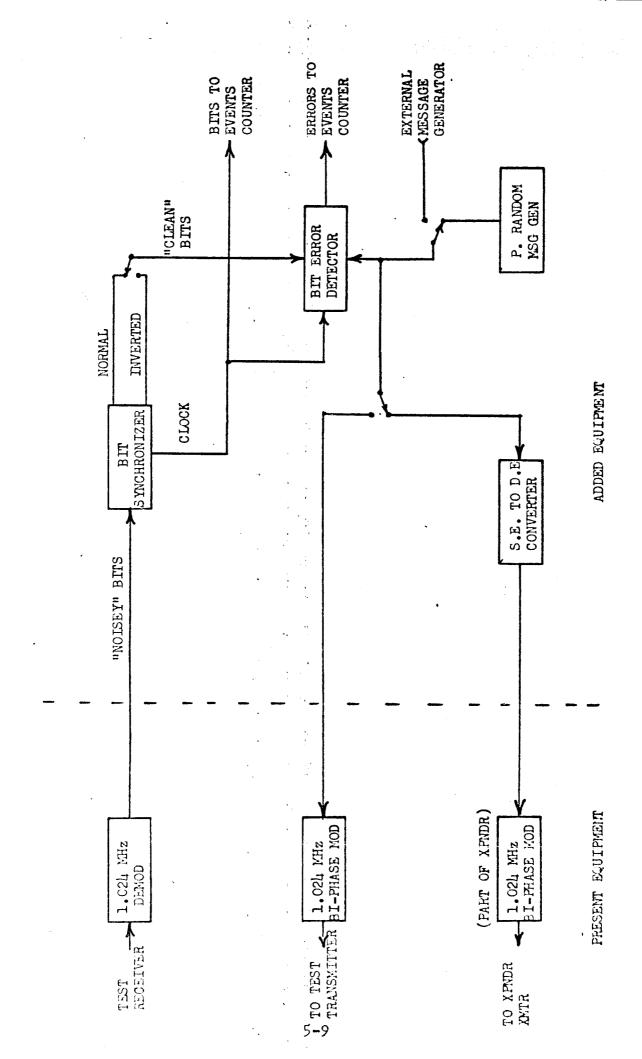


Figure 5-4. PCM Bit Error Detector

select the present (static) method or the dynamic method. There are several ways that the last two items could be accomplished. One way is shown in the block diagram, Figure 5-5.

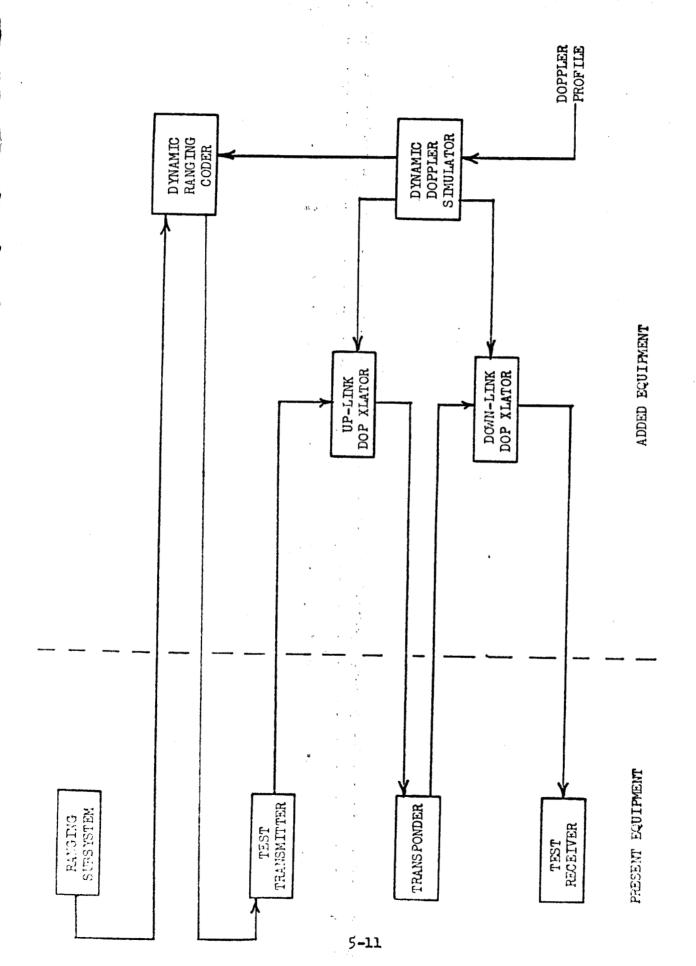


Figure 5-5. Dynamic Range and Doppler Simulator

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